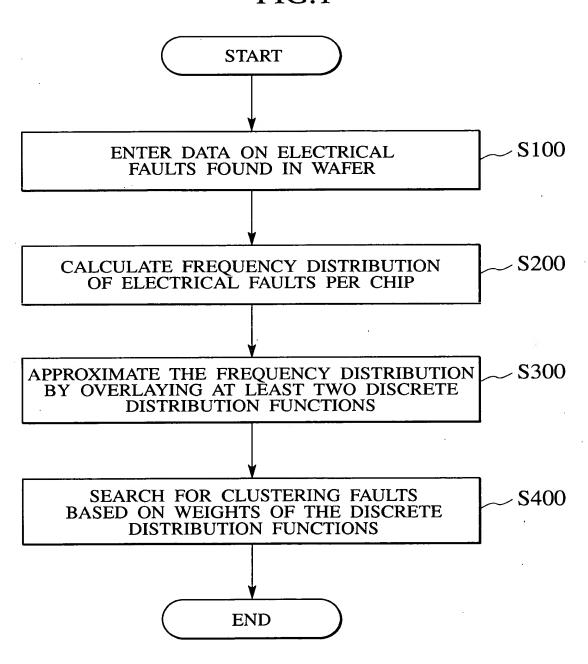
FIG.1



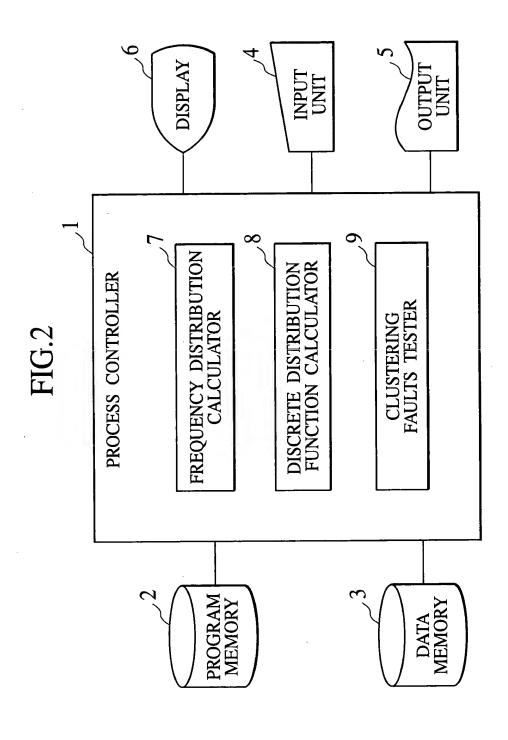


FIG.3 **START** S102 S101 ENTER THE NUMBER OF ELECTRICAL FAULTS ENTER THRESHOLD W_{NB}(th) FOUND IN EACH CHIP S200 CALCULATE FREQUENCY DISTRIBUTION OF ELECTRICAL FAULTS PER CHIP S300 APPROXIMATE THE FREQUENCY DISTRIBUTION BY OVERLAYING AT LEAST TWO DISCRETE **DISTRIBUTION FUNCTIONS** S401 IF $W_{NB} \leq W_{NB}(th)$ THEN NO CLUSTERING FAULTS AND IF WNB > WNB(th) THEN THERE ARE CLUSTERING FAULTS

END

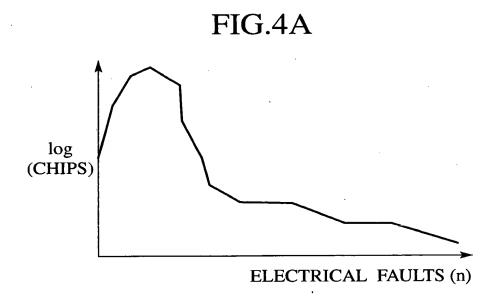


FIG.4B

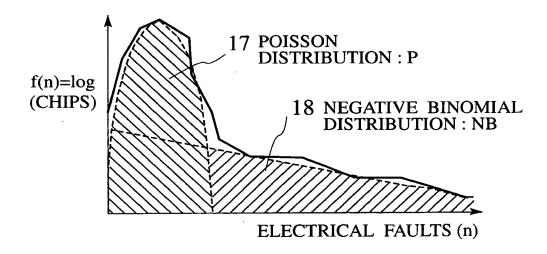
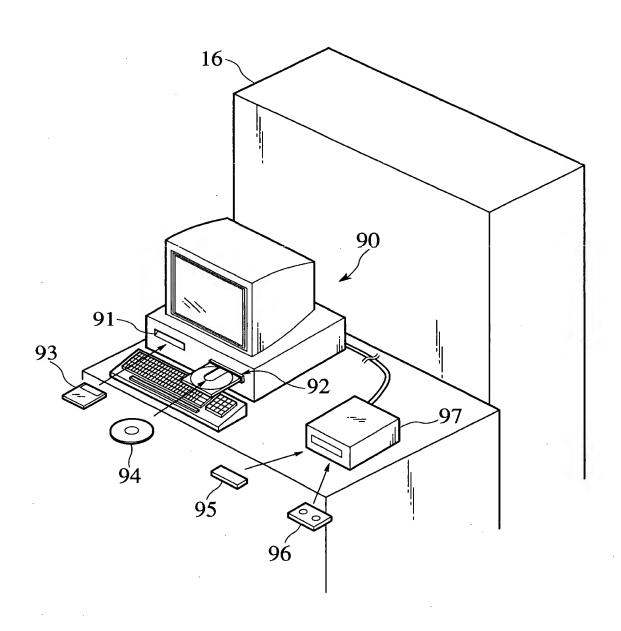


FIG.5



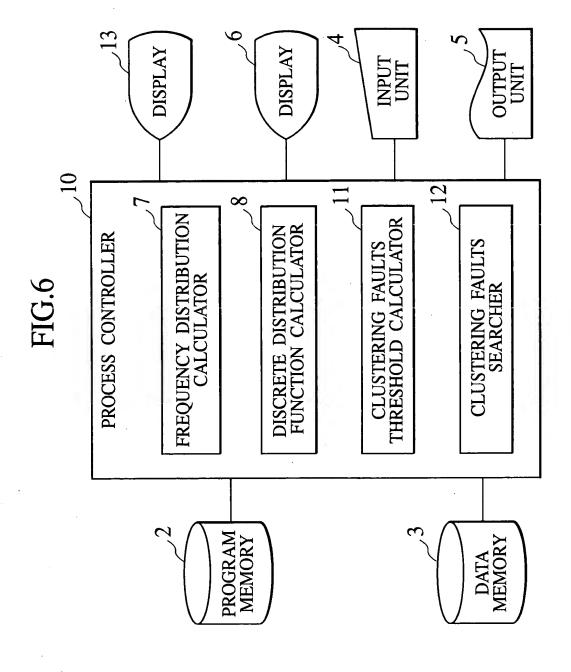
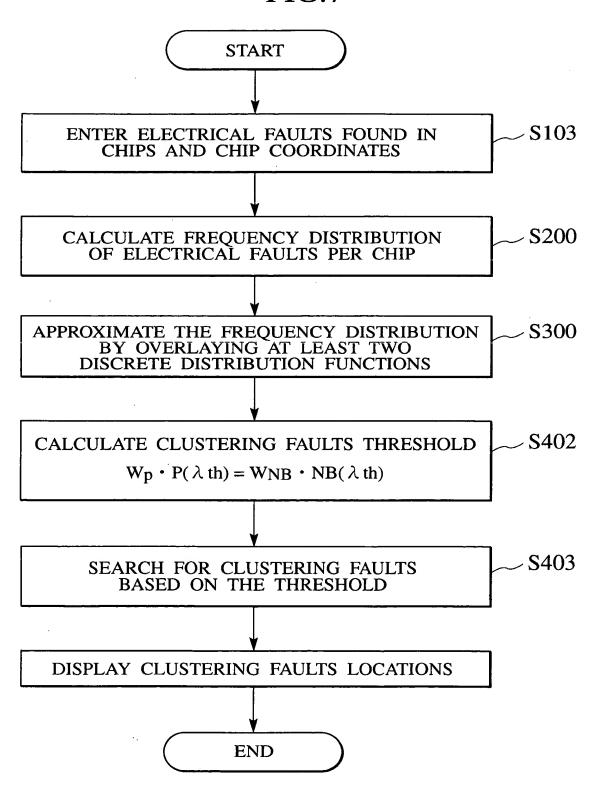


FIG.7



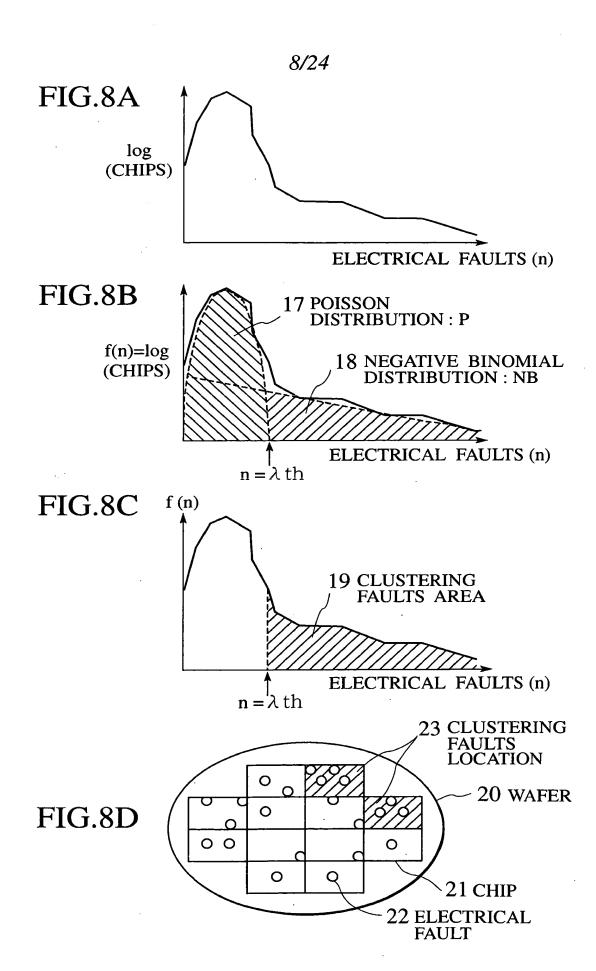
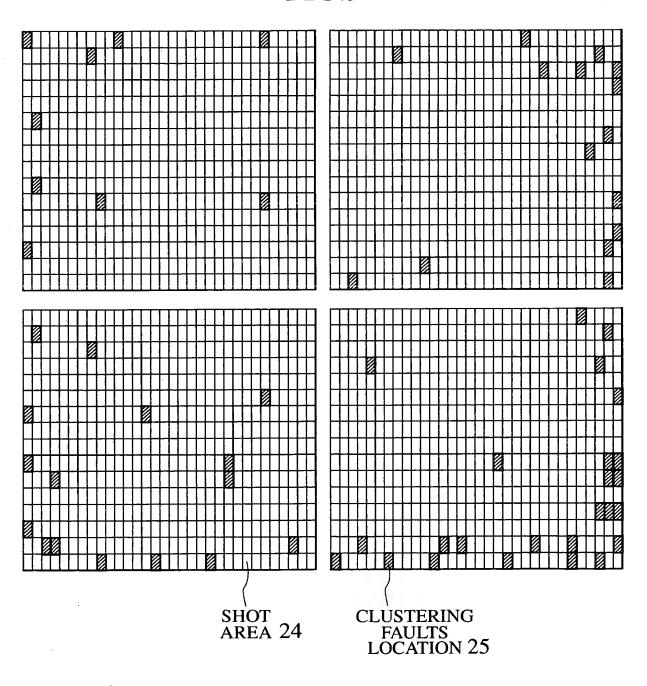


FIG.9



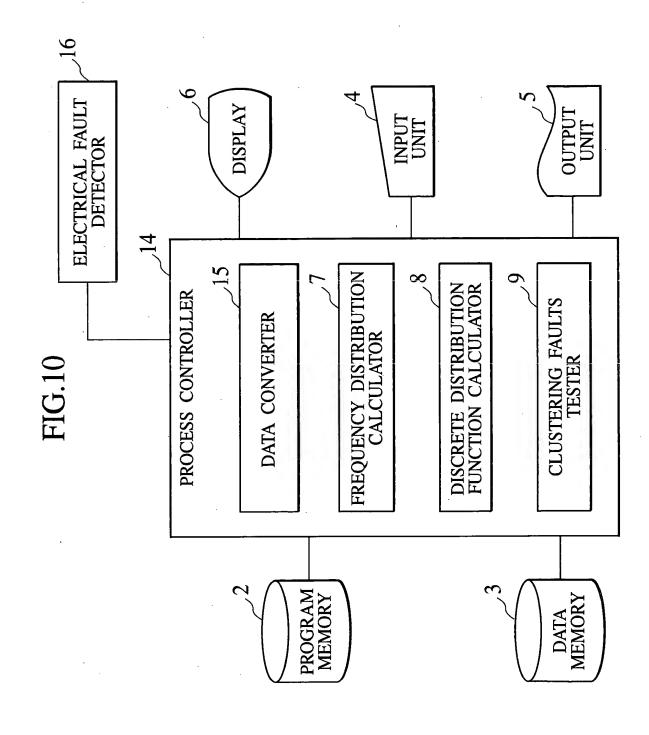


FIG.11

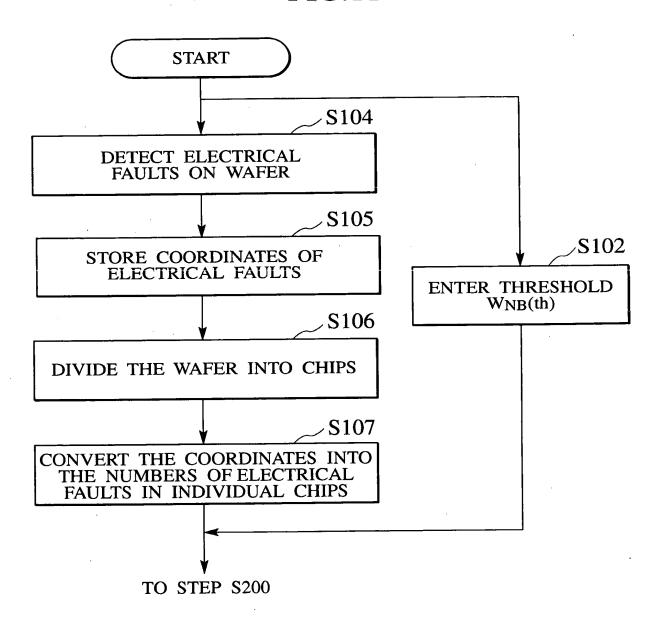
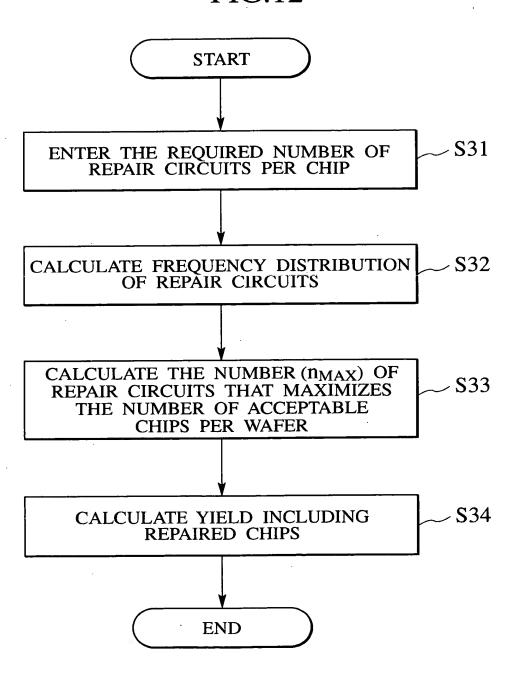


FIG.12





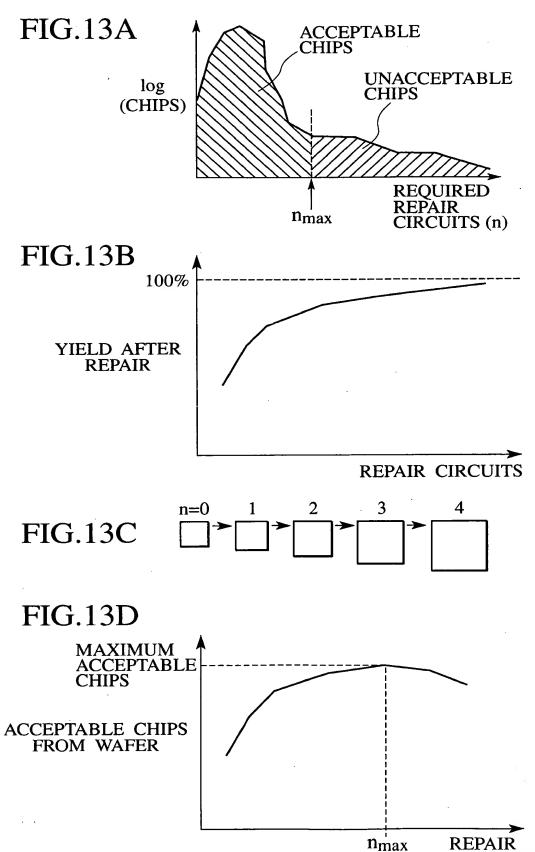


FIG.14

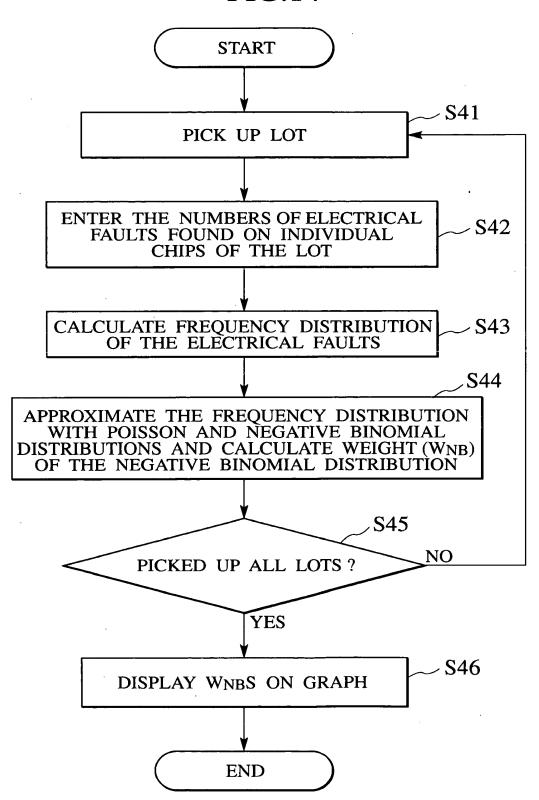
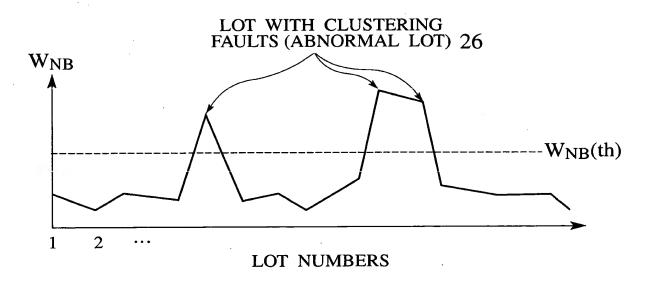
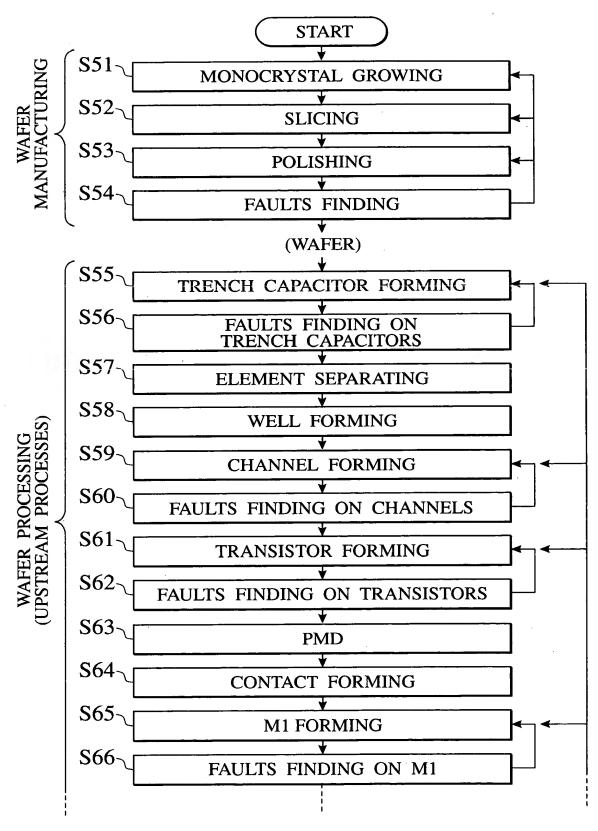


FIG.15



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FIG.16



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FIG.17

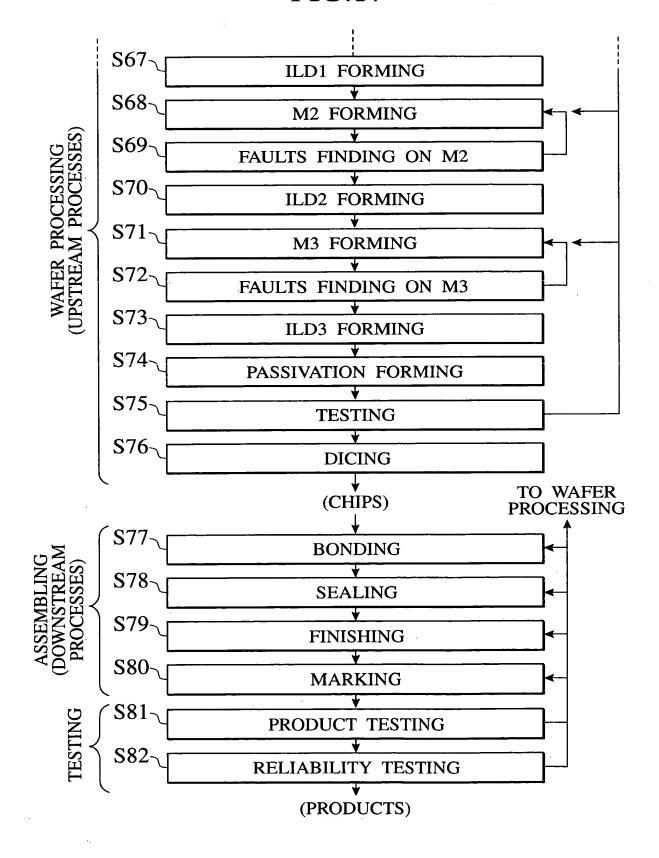


FIG.18

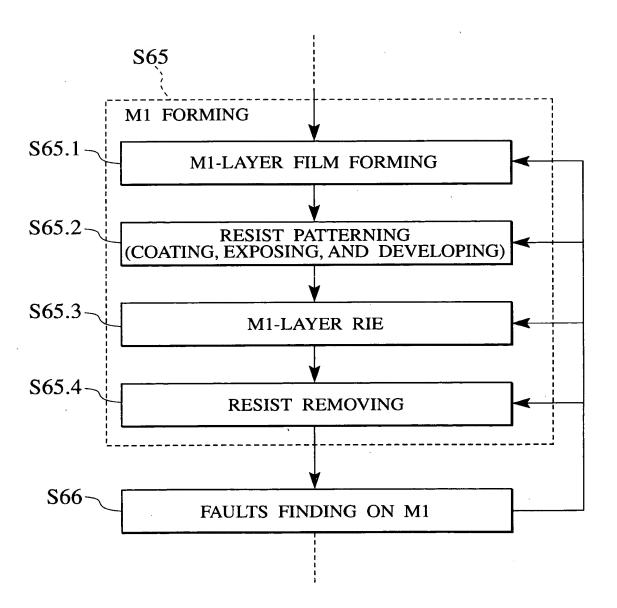


FIG.19

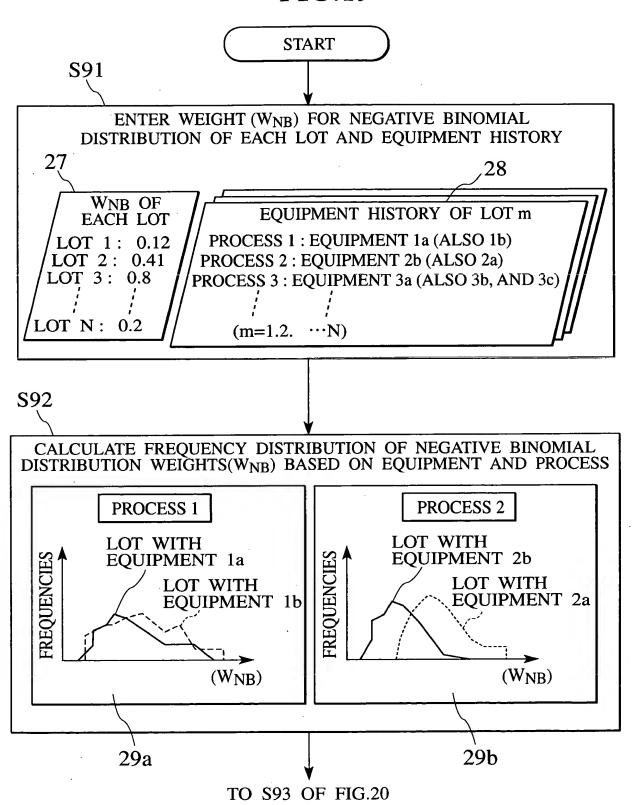
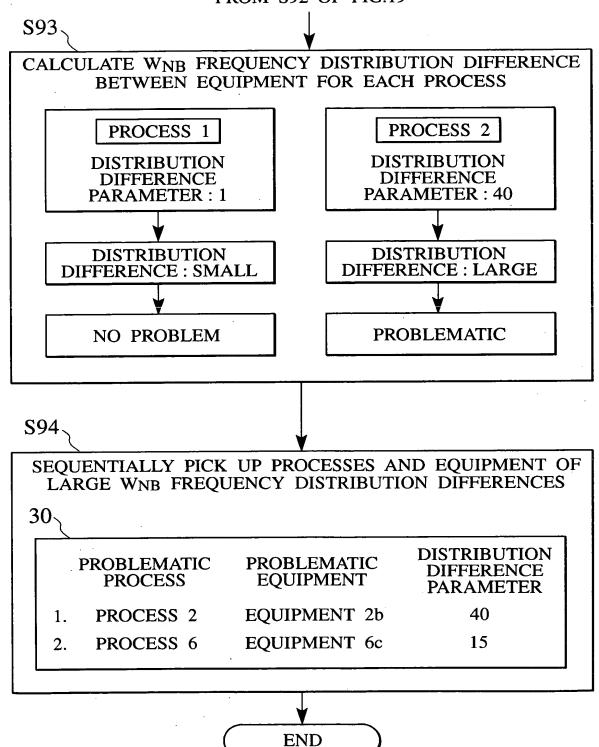
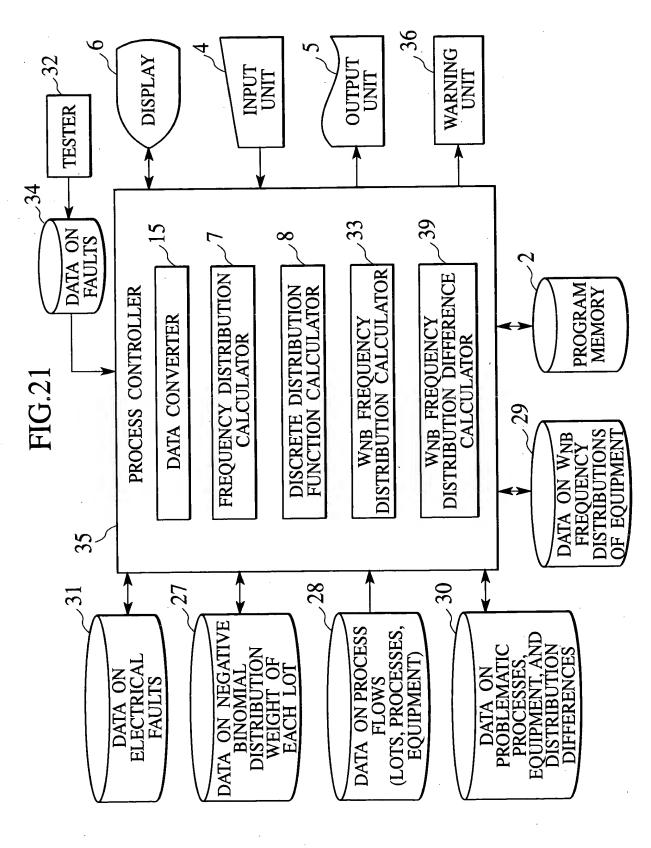


FIG.20

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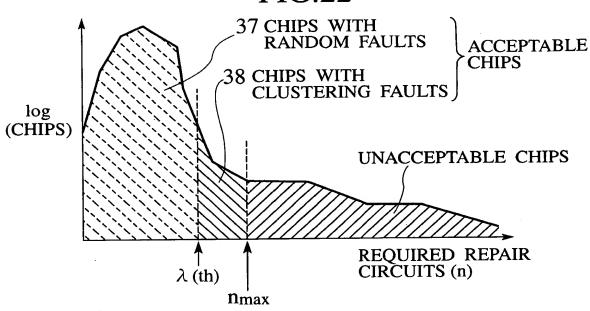
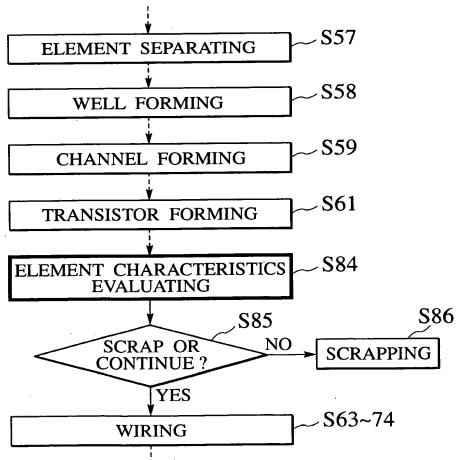


FIG.23



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